## Notice of References Cited Application/Control No. 10/829,333 Examiner Jivka Rabovianski Applicant(s)/Patent Under Reexamination SUN ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2002/0067376 A1	06-2002	Martin et al.	345/810
*	В	US-2003/0007568 A1	01-2003	Hamery et al.	375/240.26
*	С	US-2003/0216846 A1	11-2003	Chang, Ryan	701/36
*	D	US-2003/0218064 A1	11-2003	Conner et al.	235/439
*	E	US-2004/0019906 A1	01-2004	Shintani et al.	725/39
*	F	US-2004/0252966 A1	12-2004	Holloway et al.	386/046
*	G	US-2005/0158038 A1	07-2005	Dettinger et al.	386/109
*	Н	US-2006/0190256 A1	08-2006	Stephanick et al.	704/252
*	1	US-7,113,693 B1	09-2006	Chatani et al.	386/94
*	J	US-7,136,571 B1	11-2006	Dagtas, Serhan	386/68
	к	US-			
	L	US-	19 - Y		
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	Р					
	Q					
	R					
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## **NON-PATENT DOCUMENTS**

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*	ļ	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.